

10/590388

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<b>INFORMATION DISCLOSURE STATEMENT TRANSMITTAL</b>  To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.	<b>Application Number</b>	
	<b>Filing Date</b>	
	<b>First Named Inventor</b>	DE CLERCQ, MARK N., O.
	<b>Group Art Unit</b>	
	<b>Examiner Name</b>	
	<b>Atty. Docket Number</b>	NL04 0156 US1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number No.-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
	1	US- 2003/132777	07/17/2003	LAACKMANN PETER ET AL.	
	2	US- 2003/218475	11/27/2003	GAMMEL BERNDT	
	3	US- 5 861 652	01/19/1999	COLE ET AL.	
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Document Number (ctry <sup>3</sup> -no.-kind <sup>5</sup> , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>

NON-PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T <sup>6</sup>
	1	I. RAYANE ET AL: "A DIGITAL BIST FOR OPERATIONAL AMPLIFIERS EMBEDDED IN MIXED-SIGNAL CIRCUITS"; PROCEEDINGS OF IEEE VLSI TEST SYMPOSIUM; 1999 PP 304-310.				
	2	KHALKHAL A ET AL: "ON-CHIP MEASUREMENT OF INTERCONNECT CAPACITANCES IN A CMOS PROCESS"; PROCEEDINGS OF THE INTERNATIONAL CONF. ON MICROELECTRONIC TEST STRUCTURES NARA JP; MAR 22-25 1995; N.Y. IEEE US; 22 MAR 1995; PP 145-149				

<b>Examiner Signature</b>		<b>Date Considered</b>	
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